

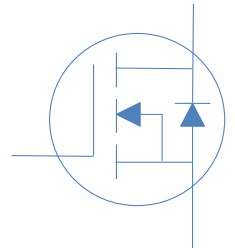
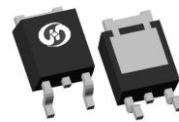
100V N-Ch Power MOSFET

E

C
C

E

V_{DS}		100	V
$R_{DS(on),typ}$	$V_{GS}=10V$	4.8	m
I_D (Silicon Limited)		115	A



Part Number	Package	Marking
HGD050N10A	TO-252	GD050N10A

Absolute Maximum Ratings at T_J

Parameter	Symbol	Conditions	Value	Unit
Continuous Drain Current (Silicon Limited)	I_D	T_C	115	A
		T_C	81	
Drain to Source Voltage	V_{DS}	-	100	V
Gate to Source Voltage	V_{GS}	-	20	V
Pulsed Drain Current	I_{DM}	-	400	A
Avalanche Energy, Single Pulse	E_{AS}	$L=0.1mH, T_C$	80	mJ
Power Dissipation	P_D	T_C	150	W
Operating and Storage Temperature	T_J, T_{stg}	-	-55 to 175	

Absolute Maximum Ratings

Parameter	Symbol	Max	Unit
Thermal Resistance Junction-Case	R	1	
Thermal Resistance Junction-Ambient	R	46	

Electrical Characteristics at T_j Static Characteristics

Parameter	Symbol	Conditions	Value			Unit
			min	typ	max	
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250\text{ A}$	100	-	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=250\text{ A}$	2	3	4	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{GS}=0V, V_{DS}=100V, T_j$	-	-	1	A
		$V_{GS}=0V, V_{DS}=100V, T_j$	-	-	100	
Gate to Source Leakage Current	I_{GSS}	V_{GS} $V_{DS}=0V$	-	-	100	nA
Drain to Source on Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=20A$	-	4.8	5.3	m
Transconductance	g_{fs}	$V_{DS}=5V, I_D=20A$	-	60	-	S
Gate Resistance	R_G	$V_{GS}=0V, V_{DS}\text{ Open}, f=1\text{MHz}$	-	1.2	-	

Dynamic Characteristics

Input Capacitance	C_{iss}		-	3490	-	
Output Capacitance	C_{oss}	$V_{GS}=0V, V_{DS}=50V, f=1\text{MHz}$	-	571	-	pF
Reverse Transfer Capacitance	C_{rss}		-	18	-	
Total Gate Charge	Q_g		-	47	-	
Gate to Source Charge	Q_{gs}	$V_{DD}=50V, I_D=20A, V_{GS}=10V$	-	10	-	nC
Gate to Drain (Miller) Charge	Q_{gd}		-	10	-	
Turn on Delay Time	$t_{d(on)}$		-	-	-	
		$V_{DD}=50V, I_D=20A, V_{GS}=10V,$	-	7	-	
		$R_G=10\ \Omega$	-	25	-	
			-	5	-	

Reverse Diode Characteristics

Reverse Recovery Time	t_{rr}	$V_R=50V, I_F=20A, dI_F/dt=500A/\text{s}$	-	50	-	ns
Reverse Recovery Charge	Q_{rr}		-	350	-	nC

Fig 1. Typical Output Characteristics

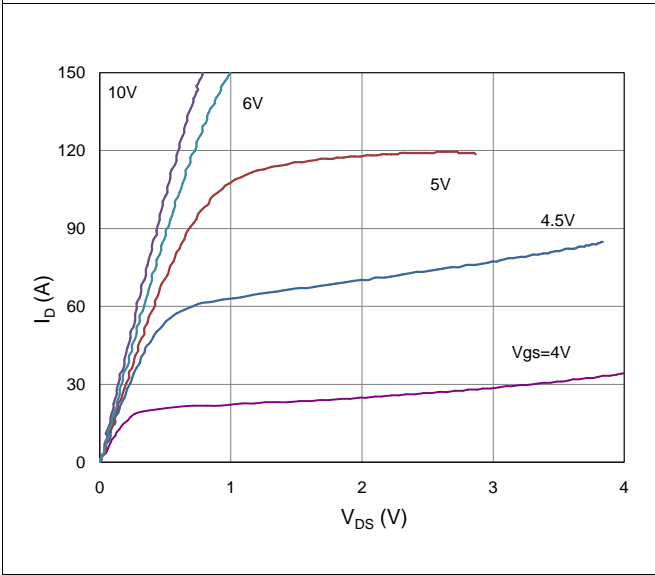


Figure 2. On-Resistance vs. Gate-Source Voltage

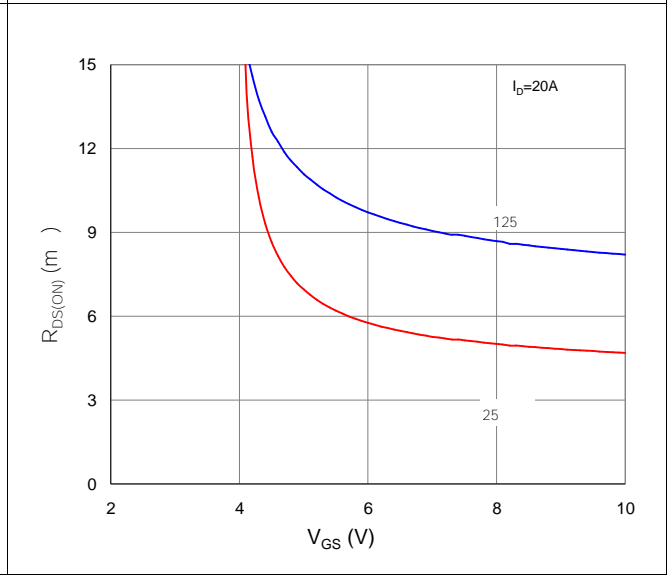


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

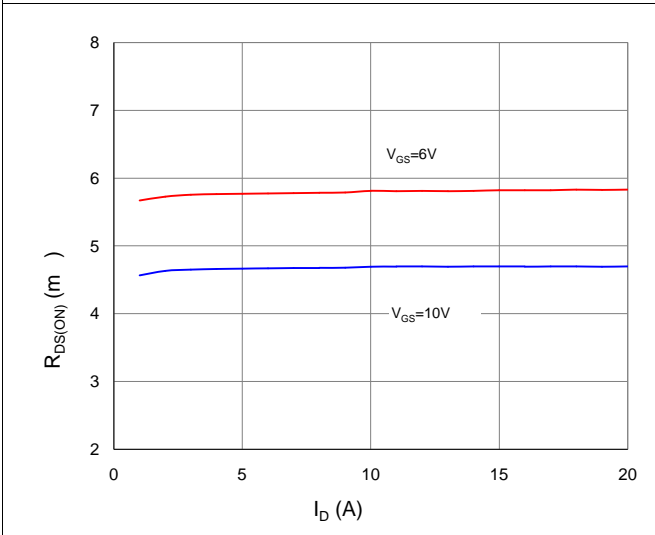


Figure 4. Normalized On-Resistance vs. Junction Temperature

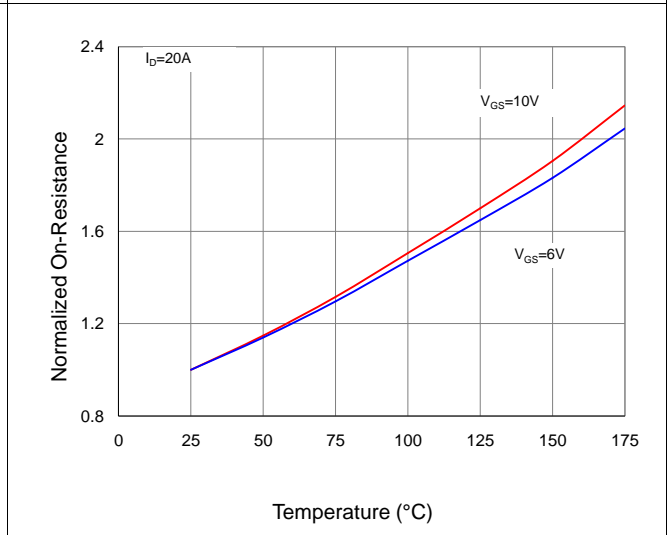


Figure 5. Typical Transfer Characteristics

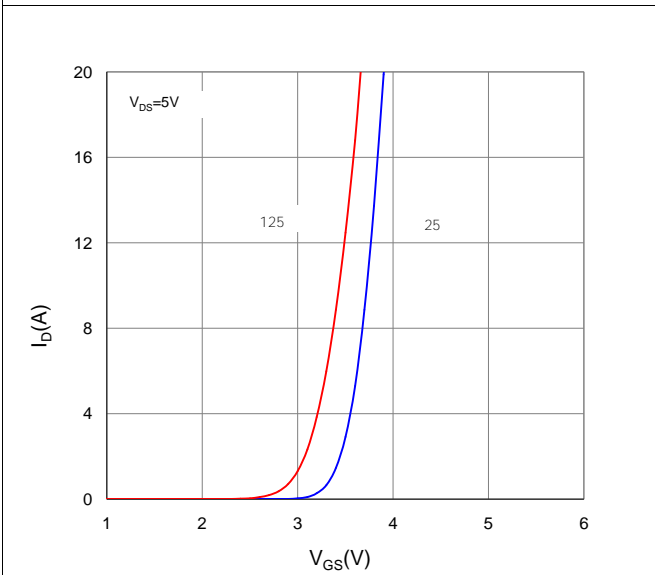
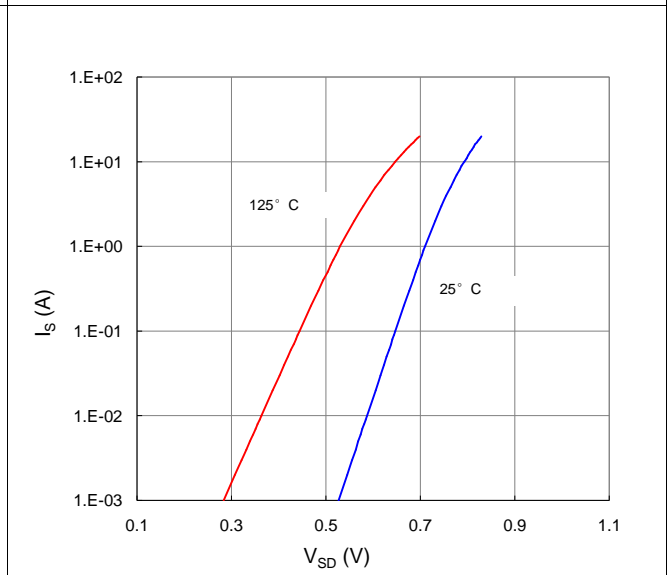


Figure 6. Typical Source-Drain Diode Forward Voltage

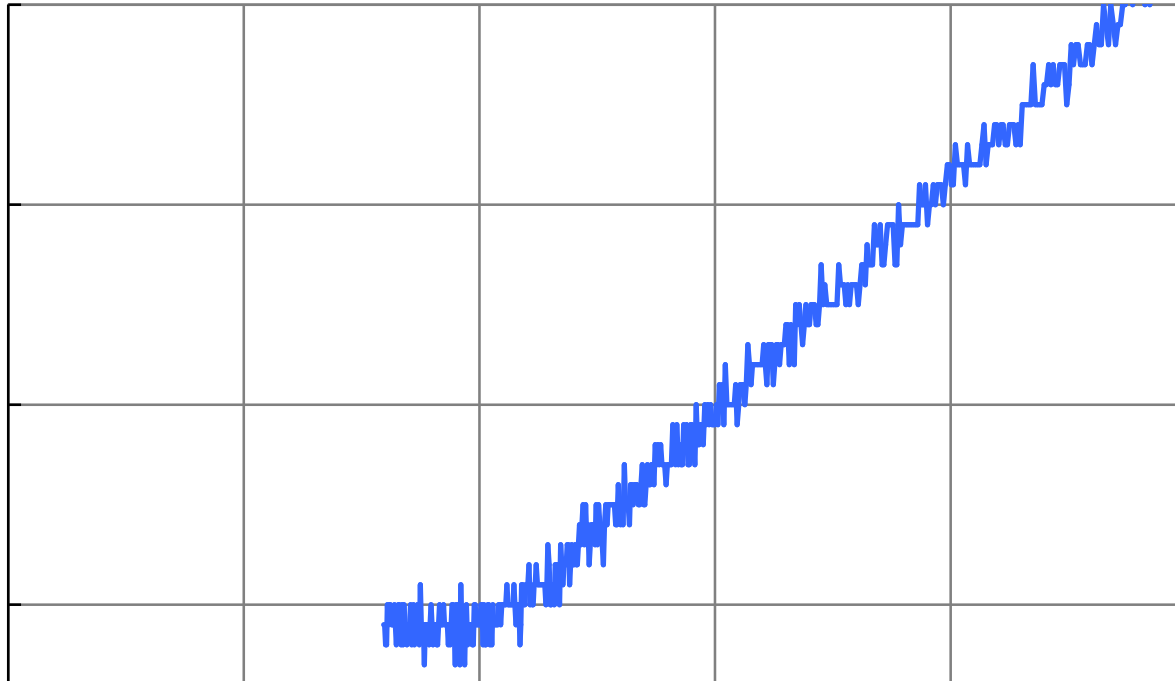


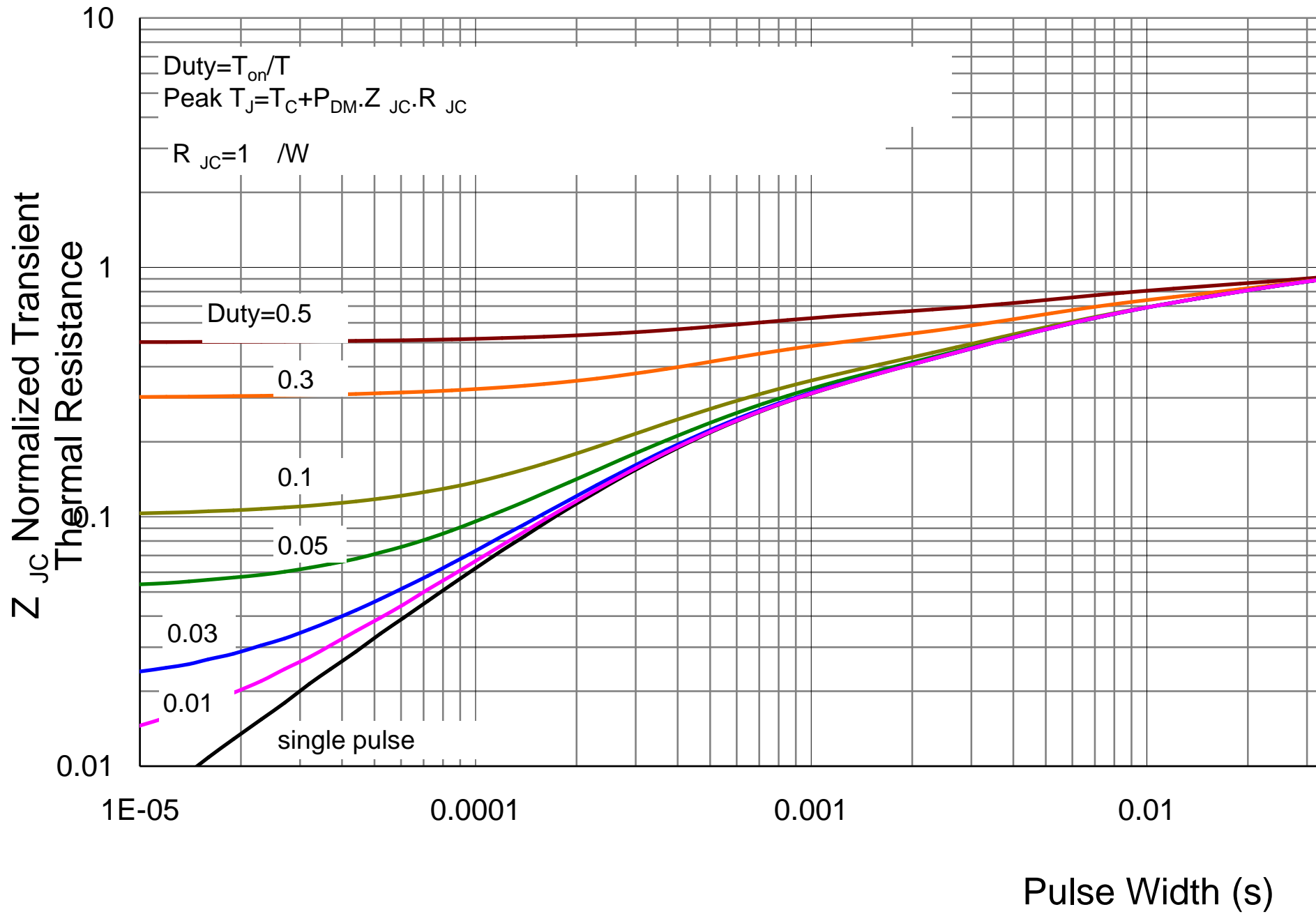


HGD050N10A

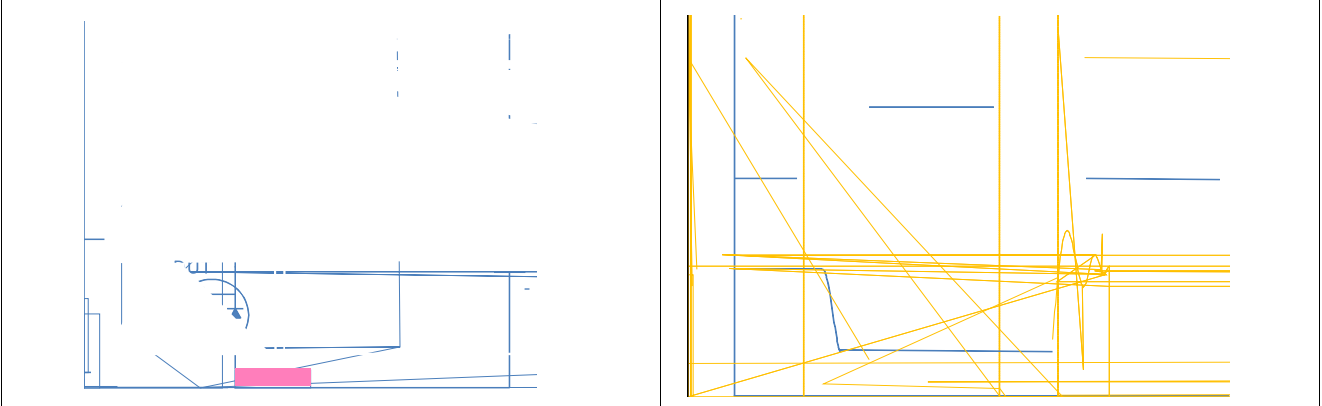
Figure 7. Typical Gate-Charge vs. Gate-to-Source Voltage

Figure 8.

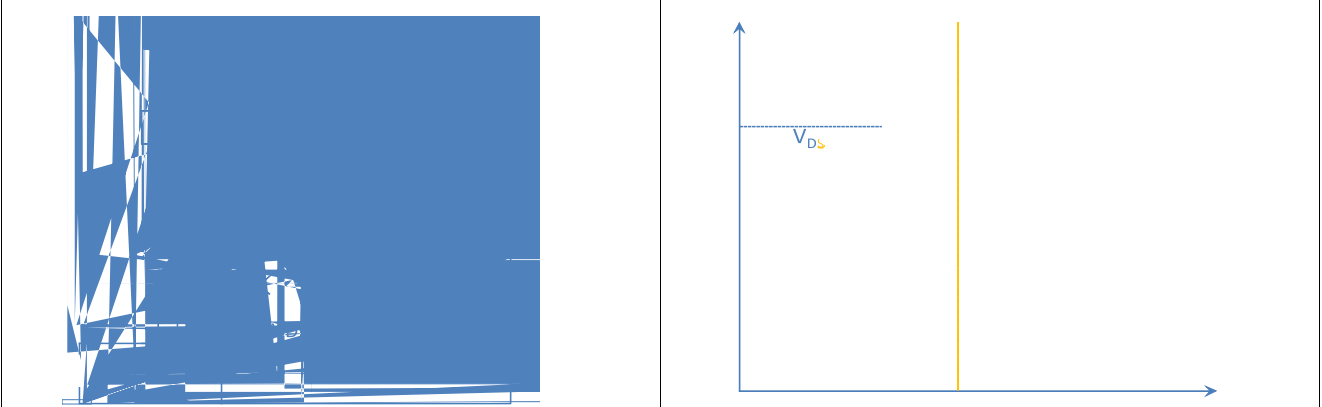




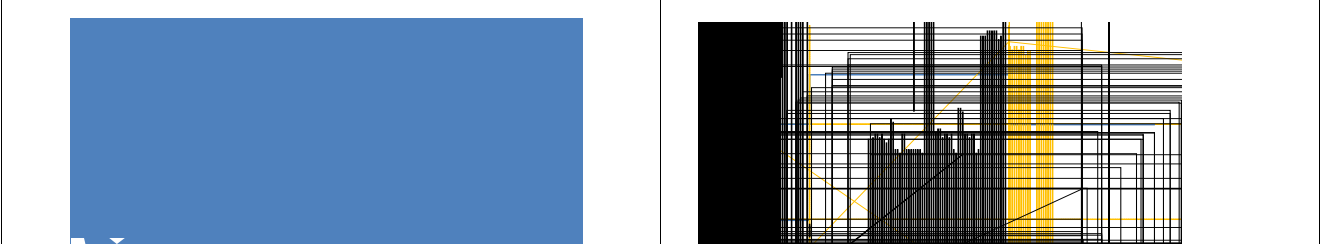
Inductive switching Test

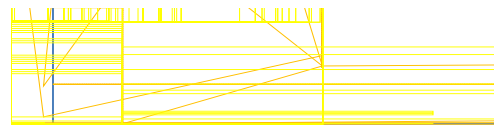


Gate Charge Test

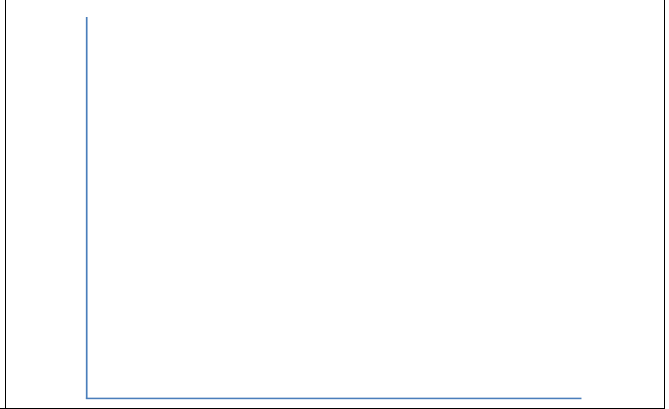
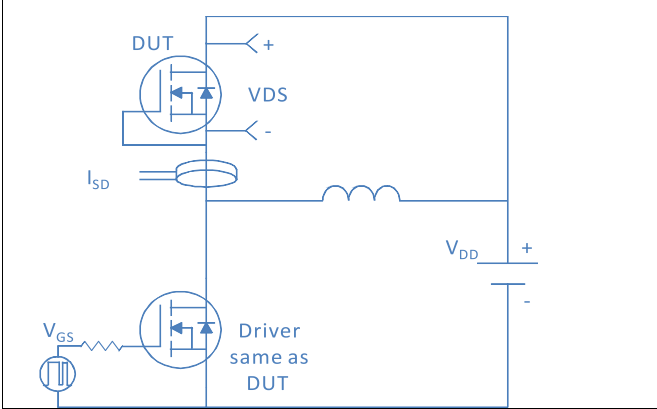


Uclamped Inductive Switching (UIS) Test



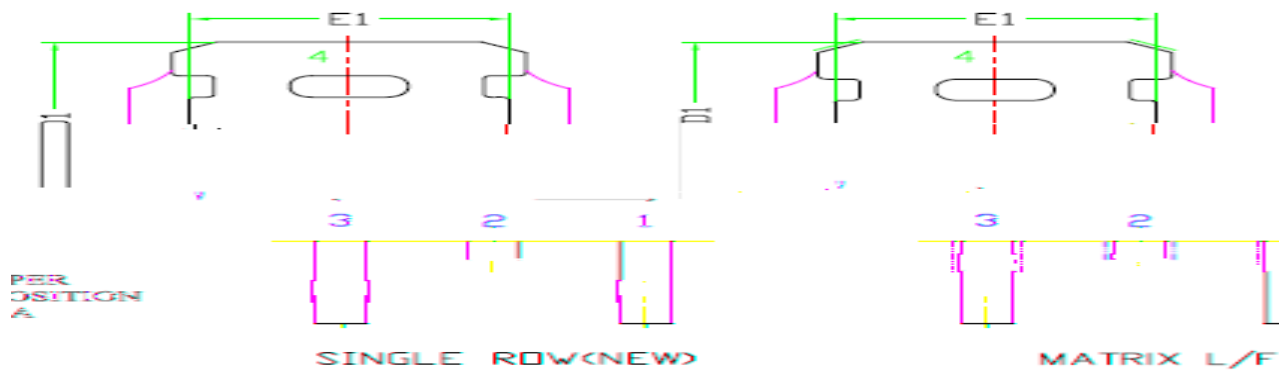


Diode Recovery Test



Ver 1.0

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Ver 1.0